

CY7C1021V

Features

- 3.3V operation (3.0V–3.6V)
- · High speed
 - —t_{AA} = 10/12/15 ns
- · CMOS for optimum speed/power
- Low active power (L version) — 540 mW (max.)
- Low CMOS Standby Power (L version) -1.08 mW (max.)
- Automatic power-down when deselected
- · Independent Control of Upper and Lower bits
- · Available in 44-pin TSOP II and 400-mil SOJ

Functional Description

The CY7C1021V is a high-performance CMOS static RAM organized as 65,536 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

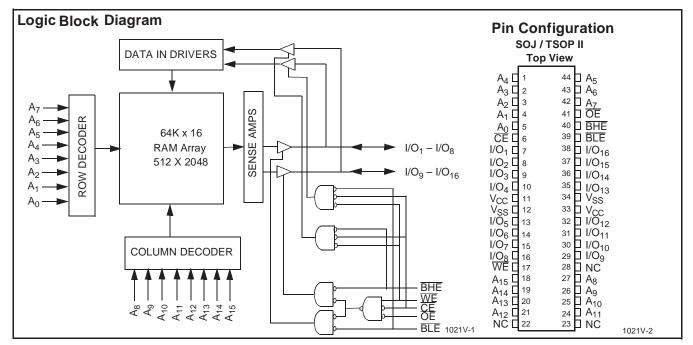
64K x 16 Static RAM

Writing to the device is accomplished by taking chip enable (CE) and write enable (WE) inputs LOW. If byte low enable (BLE) is LOW, then data from I/O pins (I/O1 through I/O8), is written into the location specified on the address pins (A0 through A₁₅). If byte high enable (BHE) is LOW, then data from I/O pins $(I/O_9 \text{ through } I/O_{16})$ is written into the location specified on the address pins (A_0 through A_{15}).

Reading from the device is accomplished by taking chip enable (\overline{CE}) and output enable (\overline{OE}) LOW while forcing the write enable (WE) HIGH. If byte low enable (BLE) is LOW, then data from the memory location specified by the address pins will appear on I/O_1 to I/O_8 . If byte high enable (BHE) is LOW, then data from memory will appear on I/O₉ to I/O₁₆. See the truth table at the back of this datasheet for a complete description of read and write modes.

The input/output pins $(I/O_1 \text{ through } I/O_{16})$ are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation (CE LOW. and WE LOW).

The CY7C1021V is available in 400-mil-wide SOJ and standard 44-pin TSOP Type II packages.



Selection Guide

			7C1021V-10	7C1021V-12	7C1021V-15
Maximum Access Time (ns)	10	12	15		
Maximum Operating Current (mA)	Commercial		210	200	190
		L	160	150	140
Maximum CMOS Standby Current (mA)	Commercial		5	5	5
		L	0.300	0.300	0.300

Shaded areas contain advance information.



Maximum Ratings

(Above which the useful life may be impaired. For user guide-lines, not tested.)
Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage on V_{CC} to Relative $GND^{[1]}$ 0.5V to +4.6V
DC Voltage Applied to Outputs in High Z State ^[1] 0.5V to V _{CC} +0.5V DC Input Voltage ^[1] 0.5V to V _{CC} +0.5V

Current into Outputs (LOW) 20 mA Static Discharge Voltage>2001V (per MIL-STD-883, Method 3015)

Latch-Up Current......>200 mA

Operating Range

Range	Ambient Temperature ^[2]	v _{cc}
Commercial	0°C to +70°C	3.3V ± 10%
Industrial	−40°C to +85°C	3.3V ± 10%

Electrical Characteristics Over the Operating Range

		Test Conditions		7C102	21V-10	7C102	21V-12	7C1021V-15		
Parameter	Description			Min.	Max.	Min.	Max.	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	$V_{CC} = Min., I_{OH} = -4.0 m$	۱A	2.4		2.4		2.4		V
V _{OL}	Output LOW Voltage	$V_{CC} = Min., I_{OL} = 8.0 mA$	٨		0.4		0.4		0.4	V
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3V	2.0	V _{CC} + 0.3V	2.0	V _{CC} + 0.3V	V
V _{IL}	Input LOW Voltage ^[1]			-0.3	0.8	-0.3	0.8	-0.3	0.8	V
I _{IX}	Input Load Current	$GND \le V_I \le V_{CC}$		-1	+1	-1	+1	-1	+1	μA
I _{OZ}	Output Leakage Current	$GND \le V_I \le V_{CC},$ Output Disabled		-2	+2	-2	+2	-2	+2	μA
I _{CC}	V _{CC} Operating	V _{CC} = Max.,			210		200		190	mA
	Supply Current $I_{OUT} = 0 \text{ mÅ}$ $f = f_{MAX} = 1/t$		L		160		150		140	mA
I _{SB1}	Automatic CE Power-Down Current —TTL Inputs	$ \begin{array}{l} \text{Max. } V_{CC}, \overline{CE} \geq V_{IH} \\ V_{IN} \geq V_{IH} \text{ or} \\ V_{IN} \leq V_{IL}, f = f_{MAX} \end{array} $	·		40		40		40	mA
I _{SB2}	Automatic CE	Max. V _{CC} ,			5		5		5	mA
	Power-Down Current —CMOS Inputs		L		300		300		300	μΑ

Shaded areas contain advance information.

Capacitance^[3]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	6	pF
C _{OUT}	Output Capacitance		8	pF

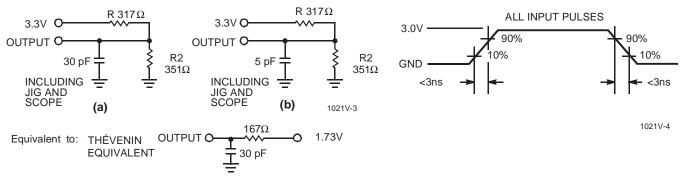
Notes:

V_{LL} (min.) = -2.0V for pulse durations of less than 20 ns.
T_A is the "instant on" case temperature.
Tested initially and after any design or process changes that may affect these parameters.





AC Test Loads and Waveforms



Switching Characteristics^[4] Over the Operating Range

		7C10	21V-10	7C1021V-12		7C1021V-15		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYC	LE		•	•		•		
t _{RC}	Read Cycle Time	10		12		15		ns
t _{AA}	Address to Data Valid		10		12		15	ns
t _{OHA}	Data Hold from Address Change	3		3		3		ns
t _{ACE}	CE LOW to Data Valid		10		12		15	ns
t _{DOE}	OE LOW to Data Valid		5		6		7	ns
t _{LZOE}	OE LOW to Low Z	0		0		0		ns
t _{HZOE}	OE HIGH to High Z ^[5, 6]		5		6		7	ns
t _{LZCE}	CE LOW to Low Z ^[6]	3		3		3		ns
t _{HZCE}	CE HIGH to High Z ^[5, 6]		5		6		7	ns
t _{PU}	CE LOW to Power-Up	0		0		0		ns
t _{PD}	CE HIGH to Power-Down		12		12		15	ns
t _{DBE}	Byte enable to Data Valid		5		6		7	ns
t _{LZBE}	Byte enable to Low Z	0		0		0		ns
t _{HZBE}	Byte disable to High Z		5		6		7	ns
WRITE CYC	LE ^[7]		•	•		•		
t _{WC}	Write Cycle Time	10		12		15		ns
t _{SCE}	CE LOW to Write End	8		8		10		ns
t _{AW}	Address Set-Up to Write End	7		8		10		ns
t _{HA}	Address Hold from Write End	0		0		0		ns
t _{SA}	Address Set-Up to Write Start	0		0		0		ns
t _{PWE}	WE Pulse Width	7		8		10		ns
t _{SD}	Data Set-Up to Write End	5		6		8		ns
t _{HD}	Data Hold from Write End	0		0		0		ns
t _{LZWE}	WE HIGH to Low Z ^[6]	3		3		3		ns
t _{HZWE}	WE LOW to High Z ^[5, 6]		5		6		7	ns
t _{BW}	Byte enable to end of write	7		8		9		ns

Shaded areas contain advance information

Notes:

Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.

 t_{HZOE} , t_{HZEE} , t_{HZEE} , t_{HZCE} , and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZOE} , and t_{HZWE} for any given device. The internal write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE / BLE LOW. CE, WE and BHE / BLE must be LOW to initiate a write, 5.

6.

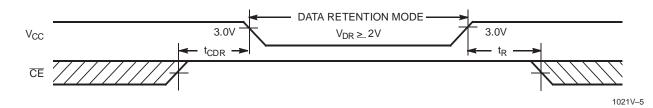
7. and the transition of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.



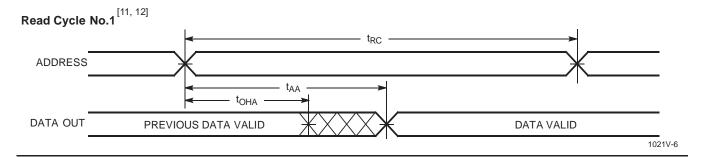
Data Retention Characteristics Over the Operating Range (L version only)

Parameter	Description		Conditions ^[10]	Min.	Max.	Unit
V _{DR}	V _{CC} for Data Retention			2.0		V
ICCDR	Data Retention Current	Com'l	$\label{eq:V_CC} \begin{split} & \frac{V_{CC} = V_{DR} = 2.0V,}{CE \geq V_{CC} - 0.3V,} \\ & V_{IN} \geq V_{CC} - 0.3V \text{ or} \\ & V_{IN} \leq 0.3V \end{split}$		100	μΑ
t _{CDR} ^[8]	Chip Deselect to Data Reter	ntion Time		0		ns
t _R ^[9]	Operation Recovery Time			t _{RC}		ns

Data Retention Waveform



Switching Waveforms



Notes:

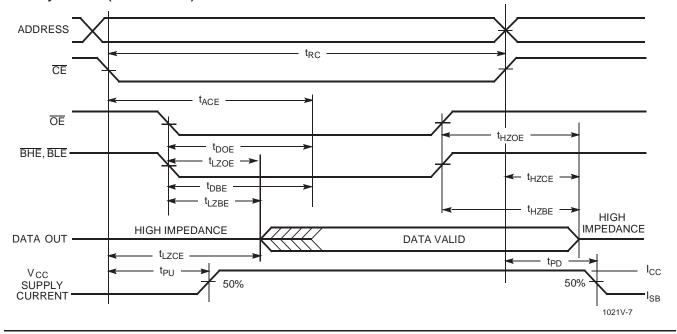
8. Tested initially and after any design or process changes that may affect these parameters. 9. $t_r \le 3$ ns for the -12 and -15 speeds. $t_r \le 5$ ns for the -20 and slower speeds. 10. No input may exceed V_{CC} + 0.5V. 11. Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} and/or $\overline{BHE} = V_{IL}$ 12. \overline{WE} is HIGH for read cycle.



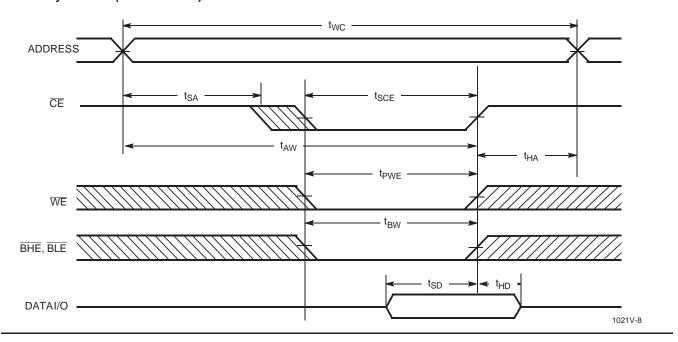
PRELIMINARY

Switching Waveforms (continued)

Read Cycle No.2 ($\overline{\text{OE}}$ Controlled) [12, 13]



Write Cycle No. 1 (CE Controlled) [14, 15]



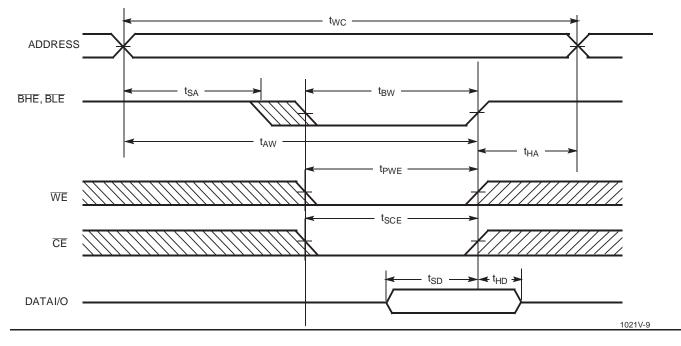
Notes:

Address valid prior to or coincident with CE transition LOW.
Data I/O is high impedance if OE or BHE and/or BLE= V_{IH}.
If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

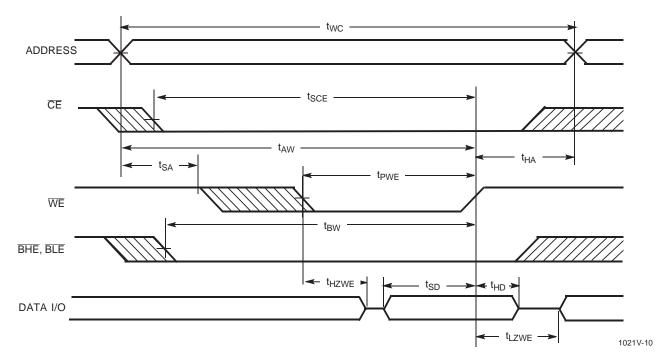


Switching Waveforms (continued)

Write Cycle No. 2 (BLE or BHE Controlled)



Write Cycle No.3 (WE Controlled, OE LOW)





Truth Table

CE	ŌĒ	WE	BLE	BHE	I/O ₁ –I/O ₈	I/O ₉ –I/O ₁₆	Mode	Power
Н	Х	Х	Х	Х	High Z	High Z	Power-Down	Standby (I _{SB})
L	L	Н	L	L	Data Out	Data Out	Read - All bits	Active (I _{CC})
			L	Н	Data Out	High Z	Read - Lower bits only	Active (I _{CC})
			Н	L	High Z	Data Out	Read - Upper bits only	Active (I _{CC})
L	Х	L	L	L	Data In	Data In	Write - All bits	Active (I _{CC})
			L	Н	Data In	High Z	Write - Lower bits only	Active (I _{CC})
			Н	L	High Z	Data In	Write - Upper bits only	Active (I _{CC})
L	Н	Н	Х	Х	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})
L	Х	Х	Н	Н	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1021V33-10VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33L-10VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33-10ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C10201V33L-10ZC	Z44	44-Lead TSOP Type II	Commercial
12	CY7C1021V33-12VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33L-12VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33-12ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1021V33L-12ZC	Z44	44-Lead TSOP Type II	Commercial
15	CY7C1021V33-15VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33L-15VC	V34	44-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1021V33-15ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1021V33L-15ZC	Z44	44-Lead TSOP Type II	Commercial
	CY7C1021V33-15ZI	Z44	44-Lead TSOP Type II	Industrial

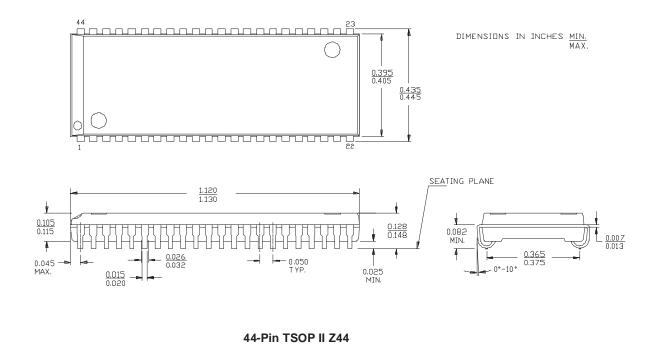
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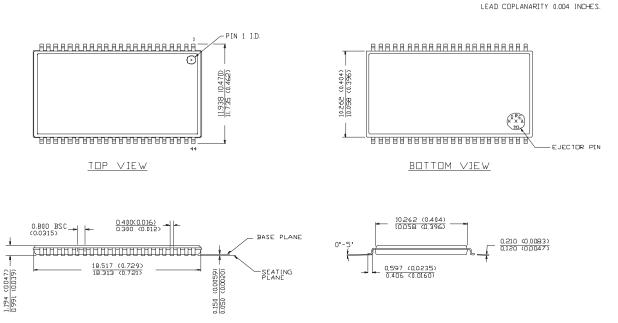


Package Diagrams

44-Lead (400-Mil) Molded SOJ V34



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